

Qualification Results Summary LTC7817/LTC7818

LTC7817/LTC7818 Reliability Report Summary			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A101</i>	3*77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3*77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1*45	Pass
High Temperature Operating Life (HTOL)	JEDEC <i>JESD22-A108</i>	3*77	Pass
Early Life Failure Rate (ELFR)	AEC-Q100-008	3*800	Pass
Latch-Up	JEDEC <i>JESD78</i>	1*5	Pass
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass

* Preconditioned per JEDEC/IPC J-STD-020



Product/Process Change Notice - PCN 23_0121 Rev. -

Analog Devices, Inc. One Analog Way, Wilmington, MA 01887, USA

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title:	LTC7817/LTC7818 Die Revision
Publication Date:	26-Sep-2023
Effectivity Date:	29-Dec-2023 <i>(the earliest date that a customer could expect to receive changed material)</i>
Revision Description:	Initial Release

Description Of Change:

A NMOS transistor has been added to ensure that a gate node of NMOS transistors are off during shutdown mode.

Reason For Change:

To optimize device performance during shutdown mode.

Impact of the change (positive or negative) on fit, form, function & reliability:

No impact to form, fit, function, or reliability.

Product Identification *(this section will describe how to identify the changed material)*

The parts that assembled with the new die will be identified by the date code.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

[ADI_PCN_23_0121_Rev_-_LTC7817_LTC7818_Qualification_Results_Summary_.p...](#)

Attachment 2: Type: Delta Qualification Matrix

[ADI_PCN_23_0121_Rev_-_PCN-Delta-Qualification-Matrix-ZVEI-5_0_16_LTC78...](#)

Note: If applicable, the device material declaration will be updated due to material change.

ADI Contact Information:

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:	Europe:	Japan:	Rest of Asia:
PCN_Americas@analog.com	PCN_Europe@analog.com	PCN_Japan@analog.com	PCN_ROA@analog.com

Appendix A - Affected ADI Models:

Added Parts On This Revision - Product Family / Model Number (25)

LTC7817 / LTC7817EUHF#PBF	LTC7817 / LTC7817EUHF#TRPBF	LTC7817 / LTC7817HUHF#WPBF	LTC7817 / LTC7817HUHF#VTRPBF	LTC7817 / LTC7817UHF#3ZZPBF
LTC7817 / LTC7817UHF#WPBF	LTC7817 / LTC7817UHF#VTRPBF	LTC7817 / LTC7817JUHF#WPBF	LTC7817 / LTC7817JUHF#VTRPBF	LTC7818 / LTC7818EUJ#PBF
LTC7818 / LTC7818EUJ#TRPBF	LTC7818 / LTC7818EUJ#WPBF	LTC7818 / LTC7818EUJ#VTRPBF	LTC7818 / LTC7818HUJ#PBF	LTC7818 / LTC7818HUJ#TRPBF
LTC7818 / LTC7818HUJ#WPBF	LTC7818 / LTC7818HUJ#VTRPBF	LTC7818 / LTC7818IUJ#PBF	LTC7818 / LTC7818IUJ#TRPBF	LTC7818 / LTC7818IUJ#WPBF
LTC7818 / LTC7818IUJ#VTRPBF	LTC7818 / LTC7818IUJ#PBF	LTC7818 / LTC7818IUJ#TRPBF	LTC7818 / LTC7818IUJ#WPBF	LTC7818 / LTC7818IUJ#VTRPBF

Appendix B - Revision History:

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	26-Sep-2023	29-Dec-2023	Initial Release